Notice of References Cited

Application/Control No. 10/662,554	Applicant(s)/I Reexamination PHAM, HIEP		
Examiner	Art Unit		
Hai L. Nguyen	2816	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,667,640	12-2003	Asano, Shigetaka	327/147
*	В	US-6,462,594	10-2002	Robinson et al.	327/159
*	С	US-6,356,158	03-2002	Lesea, Austin H.	331/11
*	D	US-6,330,296	12-2001	Atallah et al.	375/376
*	Е	US-6,215,364	04-2001	Hwang et al.	331/57
*	F	US-6,188,289	02-2001	Hyeon, Yun-jong	331/17
*	G	US-6,064,947	05-2000	Sun et al.	702/106
*	Н	US-6,043,717	03-2000	Kurd, Nasser A.	331/17
*	I	US-5,867,333	02-1999	Saiki et al.	360/51
*	J	US-5,805,024	09-1998	Takashi et al	331/17
*	К	US-5,696,468	12-1997	Nise, Benjamin E.	331/14
*	L	US-5,382,922	01-1995	Gersbach et al.	331/1A
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N			,		
	0		1/			
	Р					٠.
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	V	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.